

































































































































































































intended spreading factor. Nevertheless the complexity with a multi code / multi rate signal can be mastered by introducing appropriate definitions.

### E.3.2 Deviation

It is conceivable to regard more parameters as type „deviation' e.g. Chip frequency and RF-phase.

As chip-frequency and RF-frequency are linked together by a statement in the core specifications [1] it is sufficient to process RF frequency only.

A parameter RF-phase must be varied within the best fit process (E.2.5.). Although necessary, this parameter-variation doesn't describe any error, as the modulation schemes used in the system don't depend on an absolute RF-phase.

The parameter Timing must be varied within the best fit process (E.2.5.) This parameter variation does not describe any error, when applied to the Node B test. However when applied to the UE test, it describes the error of the UE's Timing Advance.

### E.3.3 Residual

It is conceivable to regard more parameters as type „residual' e.g. IQ origin offset. As it is not the intention of the test to separate for different error sources, but to quantify the quality of the signal, all such parameters are not extracted by the best fit process, instead remain part of EVM and PCDE.

### E.3.4 Scrambling Code

In general a signal under test can use more than one scrambling code. Note that PCDE is primarily processed to investigate the unused channelization codes. In order to know which scrambling code shall be applied on unused channelization codes, it is necessary to restrict the test conditions: The signal under test shall use exactly one scrambling code.

### E.3.5 IQ

As in FDD/uplink each channelization code can be used twice, on the I and on the Q channel, the measurement result may indicate separate values of CDP or PCDE for I and Q on which channel (I or Q) they occur.

### E.3.6 Synch Channel

A Node B signal contains a physical synch channel, which is non orthogonal, related to the other channels. In this context note: The code channel bearing the result of PCDE is exactly one of the other physical channels (never the synch channel). The origin of PCDE (erroneous code power) can be any channel (including synch channel) This means that the error due to the synch channel is projected onto the other (orthogonal) codes that make up the code domain.

### E.3.7 Formula for the minimum process

$$L (\Delta \tilde{f} , \Delta \tilde{t} , \Delta \tilde{\phi} , \Delta \tilde{g}_c , \dots , \Delta \tilde{g}_{prim} , \Delta \tilde{g}_{sec} ) = \sum_{\nu=0}^{M-1} |Z(\nu) - R(\nu)|^2$$

where:

L : the function to be minimised

The parameters to be varied in order to minimize are:

$\Delta \tilde{f}$  the RF frequency offset

$\Delta \tilde{t}$  the timing offset

- $\Delta\tilde{\varphi}$                     the phase offset
- $\Delta\tilde{g}_c \dots$                   code power offsets (one offset for each code)
- $\Delta\tilde{g}_{prim}$                   the code power offset of the primary SCH
- $\Delta\tilde{g}_{sec}$                     the code power offset of the secondary SCH
- $Z(v)$                       Samples of the signal under Test
- $R(v)$                       Samples of the reference signal
- $\sum_{v=0}^{N-1}$                     counting index  $v$  starting at the beginning of the measurement interval and ending at its end.
- $N$                           No of chips during the measurement interval.
- $Z(v)$ :                      Samples of the signal under Test. It is modelled as a sequence of complex baseband samples  $Z(\gamma)$  with a time-shift  $\Delta t$ , a frequency offset  $\Delta f$ , a phase offset  $\Delta\phi$ , the latter three with respect to the reference signal.

$$Z(v) = Z(v - \Delta\tilde{t}) * e^{-j2\pi\Delta\tilde{f}v} * e^{-j\Delta\tilde{\varphi}}$$

- $R(v)$                       Samples of the reference signal:

$$R(v) = \sum_{c=1}^{No. of codes} (g_c + \Delta\tilde{g}_c) * Chip_c(v) + (g_{prim} + \Delta\tilde{g}_{prim}) * Chip_{prim}(v) + (g_{sec} + \Delta\tilde{g}_{sec}) * Chip_{sec}(v)$$

where

- $g$                             nominal gain of the code channel
- $\Delta\tilde{g}$                       The gain offset to be varied in the minimum process
- $Chip(v)$                   is the chipsequence of the code channel
- Indices at  $g$ ,  $\Delta\tilde{g}$  and  $Chip$ : The index indicates the code channel:  $c = 1,2,\dots$  No of code channels
- prim=                      primary SCH
- sec=                        secondary SCH
- Range for  $Chip_c$ : +1,-1

### E.3.8 Power Step

If the measurement period for any code contains a power step due to power control, it is necessary to model the reference signal for that code using two gain factors.

### E.3.9 Formula for EVM

$$EVM = \sqrt{\frac{\sum_{\nu=0}^{N-1} |Z'(\gamma) - R'(\gamma)|^2}{\sum_{\nu=0}^{N-1} |R'(\gamma)|^2}} * 100 \%$$

$Z'(\gamma)$ ,  $R'(\gamma)$  are the varied measured and reference signals.

---

## Annex F (informative): Derivation of Test Requirements

The Test Requirements in this specification have been calculated by relaxing the Minimum Requirements of the core specification using the Test Tolerances defined in subclause 4.2. When the Test Tolerance is zero, the Test Requirement will be the same as the Minimum Requirement. When the Test Tolerance is non-zero, the Test Requirements will differ from the Minimum Requirements, and the formula used for this relaxation is given in tables F.1, F.2 and F.3

Note that a formula for applying Test Tolerances is provided for all tests, even those with a test tolerance of zero. This is necessary in the case that the Test System uncertainty is greater than that allowed in subclause 4.1. In this event, the excess error shall be subtracted from the defined test tolerance in order to generate the correct tightened Test Requirements as defined in subclause 4.3.

For example, a Test System having 0.9 dB accuracy for test 6.2.1 Base Station maximum output power (which is 0.2 dB above the limit specified in subclause 4.) would subtract 0.2 dB from the Test Tolerance of 0.7 dB defined in subclause 4.2. This new test tolerance of 0.5 dB would then be applied to the Minimum Requirement using the formula defined in Table F.1 to give a new range of  $\pm 2.5$  dB of the manufacturer's rated output power.

Using this same approach for the case where a test had a test tolerance of 0 dB, an excess error of 0.2 dB would result in a modified test tolerance of  $-0.2$  dB.

**Table F.1: Derivation of Test Requirements (Transmitter tests)**

Test	Minimum Requirement in TS 25.104	Test Tolerance (TT)	Test Requirement in TS 25.141
6.2.1 Base station maximum output power	In normal conditions ... within +2 dB and -2 dB of the manufacturer's rated output power In extreme conditions... within +2.5 dB and -2.5 dB of the manufacturer's rated output power	0.7 dB	Formula: Upper limit + TT Lower limit – TT In normal conditions ... within +2.7 dB and -2.7 dB of the manufacturer's rated output power In extreme conditions... within +3.2 dB and -3.2 dB of the manufacturer's rated output power
6.2.2 CPICH Power accuracy	CPICH power shall be within ±2.1dB	0.8 dB	Formula: Upper limit + TT Lower limit – TT CPICH power shall be within ±2.9dB
6.3.4 Frequency error	Frequency error limit = 0.05 ppm	12 Hz	Formula: Frequency Error limit + TT  Frequency Error limit = 0.05 ppm + 12 Hz
6.4.2 Power control steps	Lower and upper limits as specified in tables 6.9 and 6.10a	0.1 dB	Formula: Upper limits + TT Lower limits – TT 0.1 dB applied as above to tables 6.9 and 6.10a
6.4.3 Power control dynamic range	maximum power limit = BS maximum output power -3 dB minimum power limit = BS maximum output power -28 dB	1.1 dB	Formula: maximum power limit – TT minimum power limit + TT maximum power limit = BS maximum output power -4.1 dB minimum power limit = BS maximum output power -26.9 dB
6.4.4 Total power dynamic range	total power dynamic range limit = 18 dB	0.3 dB	Formula: total power dynamic range limit – TT total power dynamic range limit = 17.7 dB
6.5.1 Occupied Bandwidth	occupied bandwidth limit = 5 MHz	0 kHz	Formula: Occupied bandwidth limit + TT Occupied bandwidth limit = 5 MHz
6.5.2.1 Spectrum emission mask	Maximum level defined in tables 6.11, 6.12, 6.13 and 6.14:	1.5 dB (0 dB for the additional Band b requirements)	Formula: Maximum level + TT Add 1.5 to Maximum level entries in tables 6.11, 6.12, 6.13 and 6.14.
6.5.2.2 Adjacent Channel Leakage power Ratio (ACLR)	ACLR limit = 45 dB at 5 MHz ACLR limit = 50 dB at 10 MHz	0.8 dB	Formula: ACLR limit – TT  ACLR limit = 44.2 dB at 5 MHz ACLR limit = 49.2 dB at 10 MHz
6.5.3 Spurious emissions	Maximum level defined in tables 6.16 to 6.26	0 dB	Formula: Maximum limit + TT  Add 0 to Maximum level in tables 6.16 to 6.26
6.6 Transmit intermodulation (interferer requirements) This tolerance applies to the stimulus and not the measurements defined in 6.5.2.1, 6.5.2.2 and 6.5.3.	Wanted signal level – interferer level = 30 dB	0 dB	Formula: Ratio + TT  Wanted signal level – interferer level = 30 + 0 dB
6.7.1 EVM	EVM limit = 17.5 %	0 %	Formula: EVM limit + TT  EVM limit = 17.5%
6.7.2 Peak code Domain error	Peak code domain error limit = -33 dB	1.0 dB	Formula: Peak code domain error limit + TT  Peak code domain error limit = -32 dB

Table F.2: Derivation of Test Requirements (Receiver tests)

Test	Minimum Requirement in TS 25.104	Test Tolerance (TT)	Test Requirement in TS 25.141
7.2 Reference sensitivity	Reference sensitivity level = -121 dBm FER/BER limit = 0.001	0.7 dB	Formula: Reference sensitivity level + TT Reference sensitivity level = -120.3 dBm FER/BER limit is not changed
7.3 Dynamic range	Wanted signal level = -91 dBm AWGN level = -73 dBm/3.84 MHz	1.2 dB	Formula: Wanted signal level + TT AWGN level unchanged Wanted signal level = -89.8 dBm
7.4 Adjacent channel selectivity	Wanted signal level = -115 dBm W-CDMA interferer level = -52 dBm	0 dB	Formula: Wanted signal level + TT W-CDMA interferer level unchanged Wanted signal level = -115 dBm
7.5 Blocking characteristics	Wanted signal level = -115 dBm Interferer level See table 7.4a / 7.4b	0 dB	Formula: Wanted signal level + TT Interferer level unchanged Wanted signal level = -115 dBm
7.6 Intermod Characteristics	Wanted signal level = -115 dBm Interferer1 level (10 MHz offset CW) = -48 dBm Interferer2 level (20 MHz offset W-CDMA Modulated) = -48 dBm	0 dB	Formula: Wanted signal level + TT Interferer1 level unchanged Interferer2 level unchanged Wanted signal level = -115 dBm
7.7 Spurious Emissions	Maximum level defined in Table 7.7	0 dB	Formula: Maximum level + TT Add TT to Maximum level in table 7.7

Table F.3: Derivation of Test Requirements (Performance tests)

Test	Minimum Requirement in TS 25.104	Test Tolerance (TT)	Test Requirement in TS 25.141
8.2, Demodulation in static propagation condition	Received $E_b/N_0$ values	0.4 dB	Minimum requirement + TT
8.3, Demodulation of DCH in multipath fading conditions	Received $E_b/N_0$ values	0.6 dB	Minimum requirement + TT
8.4 Demodulation of DCH in moving propagation conditions	Received $E_b/N_0$ values	0.6 dB	Minimum requirement + TT
8.5 Demodulation of DCH in birth/death propagation conditions	Received $E_b/N_0$ values	0.6 dB	Minimum requirement + TT

## Annex G (informative): Acceptable uncertainty of Test Equipment

This informative annex specifies the critical parameters of the components of an overall Test System (e.g. Signal generators, Signal Analysers etc.) which are necessary when assembling a Test System which complies with subclause 4.1 Acceptable Uncertainty of Test System. These Test Equipment parameters are fundamental to the accuracy of the overall Test System and are unlikely to be improved upon through System Calibration.

### G.1 Transmitter measurements

**Table G.1: Equipment accuracy for transmitter measurements**

Test	Equipment accuracy	Range over which equipment accuracy applies
6.2.1 Maximum Output Power	Not critical	Not critical
6.2.2 CPICH Power accuracy	Not critical	Not critical
6.3.4 Frequency error	$\pm 10$ Hz + timebase = [12] Hz	Measurements in the range $\pm 500$ Hz.
6.4.2 Power control steps	$\pm 0.1$ dB for one 1 dB step $\pm 0.1$ dB for ten 1 dB steps	$P_{max} - 3$ dB to $P_{max} - 28$ dB
6.4.3 Power control dynamic range	$\pm 0.2$ dB relative code domain power accuracy	$P_{max} - 3$ dB to $P_{max} - 28$ dB
6.4.4 Total power dynamic range	$\pm 0.3$ dB relative error over 18 dB	$P_{max}$ to $P_{max} - 18$ dB
6.5.1 Occupied Bandwidth	$\pm 100$ kHz	$\pm 1$ MHz of the minimum requirement
6.5.2.1 Spectrum emission mask	Not critical	Not critical
6.5.2.2 ACLR	$\pm 0.8$ dB	Measurements in the range $\pm 3$ dB of the minimum requirement at signal power = $P_{max}$
6.5.3 Spurious emissions	Not critical	Not critical
6.6 Transmit intermodulation (interferer requirements)	Not critical	Not critical
6.7.1 EVM	$\pm 2.5$ % (for single code)	Measurements in the range 12.5% to 22.5% at signal power = $P_{max} - 3$ dB to $P_{max} - 18$ dB
6.7.2 Peak code Domain error	$\pm 1.0$ dB	Measurements in the range $-30$ to $-36$ dB at signal power = $P_{max}$

### G.2 Receiver measurements

**Table G.2: Equipment accuracy for receiver measurements**

Test	Equipment accuracy	Range over which equipment accuracy applies
7.2 Reference sensitivity level	Not critical	Not critical
7.3 Dynamic range	Not critical	Not critical
7.4 Adjacent channel selectivity	Not critical	Not critical
7.5 Blocking characteristics	Not critical	Not critical
7.6 Intermod Characteristics	Not critical	Not critical
7.7 Spurious Emissions	Not critical	Not critical

---

## G.3 Performance measurements

**Table G.3: Equipment accuracy for performance measurements**

<b>Test</b>	<b>Equipment accuracy</b>	<b>Range over which equipment accuracy applies</b>
8.2, Demodulation in static propagation condition	Not critical	Not critical
8.3, Demodulation of DCH in multipath fading conditions	Not critical	Not critical

---

# Annex H (Informative): UTRAN Measurement Test Cases

## H.1 Purpose of Annex

This Annex specifies test specific parameters for some of the UTRAN requirements in chapter 9.2 TS 25.133. The tests provide additional information to how the requirements should be interpreted. Some requirements may lack a test.

---

## H.2 Received Total Wideband Power

### H.2.1 Absolute RTWP measurement

1. Terminate the BS RX inputs, measure the RTWP and record it.
2. Connect a signal generator and increase the signal generator power until the reported RTWP level ( $I_{rep}$ ) has increased 3dB.
3. Measure the signal level power at the antenna connector port. This signal level is now called the "Internally generated noise" ( $N_i$ ).
4. Sweep the sum of internally generated noise ( $N_i$ ) and signal generator power ( $I$ ) through the defined accuracy range.
5. Check that:  $|N_i+I-I_{rep}|$  meets the requirements in chapter 9.2.1.

Note that  $I_o = N_i+I$

### H.2.2 Relative RTWP measurement

1. Terminate the BS RX inputs, measure the RTWP and record it.
2. Attach a signal generator to the RX input and increase the power until the by the BS reported RTWP value ( $I_{rep}$ ) has increased 3 dB.
3. Measure the signal level power at the antenna connector port. This signal level is now called the "Internally generated noise" ( $N_i$ ).
4. Calculate the required signal levels  $I$  such that the sum of the internally generated noise ( $N_i$ ) and the signal generator power ( $I$ )
5. The difference between the reported RTWP values shall meet the requirements specified in chapter 9.2.1.





RP-14	RP-010783	0126		Clarification of BMT definition for multicarrier test cases	F	3.7.0	3.8.0	
RP-14	RP-010783	0129		Correction of the definition of the PICH channel (test models)	F	3.7.0	3.8.0	
RP-14	RP-010783	0132		Correction to units and table references in Spectrum emission mask	F	3.7.0	3.8.0	
RP-14	RP-010783	0135		DPCH and S-CCPCH channel structure change to test models.	F	3.7.0	3.8.0	
RP-15	RP-020024	0144	1	Removal of BS conformance tests in SSDT mode	F	3.8.0	3.9.0	
RP-15	RP-020023	0147		Frequency error and Test model 4	F	3.8.0	3.9.0	
RP-15	RP-020023	0150		The definition of AWGN interferer	F	3.8.0	3.9.0	
RP-15	RP-020023	0153		Single and Multicarrier in spurious emission requirements	F	3.8.0	3.9.0	
RP-15	RP-020023	0159	1	Correction for FCC emission mask and frequency raster for band b (UMTS1900)	F	3.8.0	3.9.0	
RP-15	RP-020024	0171	1	Correction of power terms and definitions	F	3.8.0	3.9.0	
RP-15	RP-020023	0177		Maintenance of annex E, Global In-Channel TX-Test	F	3.8.0	3.9.0	
RP-15	RP-020024	0187	1	Correction of transmit inter modulation test method	F	3.8.0	3.9.0	
RP-15	RP-020023	0190		Correction of EVM test procedure	F	3.8.0	3.9.0	
RP-15	RP-020115	0195	2	TBD on test tolerances	F	3.8.0	3.9.0	
RP-16	RP-020286	0226		Correction of power control dynamic range Test Tolerance	F	3.9.0	3.10.0	
RP-16	RP-020286	0229	1	Correction to total power dynamic range test	F	3.9.0	3.10.0	
RP-17	RP-020468	0244		Correction of regional requirements	F	3.10.0	3.11.0	
RP-18	RP-020781	0264		FDD GSM co-existence in the Same Geographic Area	F	3.11.0	3.12.0	
RP-19	RP-030029	0270	1	Protection of the FDD BS receiver	F	3.12.0	3.13.0	
RP-29	RP-050489	0377	1	Clarification of '12.5MHz rule' and modification of the protection band for PHS	F	3.13.0	3.14.0	
RP-35	RP-070080	0443		Category B spurious emission limits for UTRA BS	F	3.14.0	3.15.0	TEI

---

## History

<b>Document history</b>		
V3.0.0	January 2000	Publication
V3.1.0	March 2000	Publication
V3.2.0	June 2000	Publication
V3.3.0	October 2000	Publication
V3.4.1	December 2000	Publication
V3.5.0	May 2001	Publication
V3.6.0	July 2001	Publication
V3.7.0	October 2001	Publication
V3.8.0	December 2001	Publication
V3.9.0	March 2002	Publication
V3.10.0	June 2002	Publication
V3.11.0	September 2002	Publication
V3.12.0	December 2002	Publication
V3.13.0	March 2003	Publication
V3.14.0	September 2005	Publication
V3.15.0	March 2007	Publication